

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

First Inventor	Joonhyung Kwon	Filing Date	December 29, 2003
Art Unit of parent application	2878	Examiner of parent application	Yam, Stephen K
Title:	Scanning Probe Microscope With Improved Probe Tip Mount (as amended herewith)		
Docket No.:	PSI004-1C US	Customer No.:	34036

Santa Clara, California  
December 29, 2003

Mail Stop PATENT APPLICATION  
COMMISSIONER FOR PATENTS  
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**PRELIMINARY AMENDMENT**

Dear Sir:

Prior to taking any action on the merits, please amend the above-identified application as follows.

**Amendments to the Specification** begin on page 2 of this paper.

**Amendments to the Claims** are reflected in the listing of claims which begins on page 6 of this paper.

**Remarks/Arguments** begin on page 9 of this paper.